## FCC ID: 2AITR-HSWL1058

## Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V05

The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)] \*  $[\sqrt{f(GHz)}] \le 3.0$  for 1-g SAR and  $\le 7.5$  for 10-g extremity SAR, where

f(GHz) is the RF channel transmit frequency in GHz;

Power and distance are rounded to the nearest mW and mm before calculation;

The result is rounded to one decimal place for comparison;

The test exclusions are applicable only when the minimum test separation distance is  $\leq$  50 mm and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion. We use 5mm as separation distance to calculate.

Maximum measured transmitter power:

## Bluetooth:

Transmit Frequency (GHz)	Mode	Measured Power (dBm)	Tune-up power (dBm)	Max tune-up	Result	1g SAR
(G112)		(dbiii)	(dbiii)	power(dBm)	calculation	
2.402	GFSK	4.00	5±1	6	1.2340	3
2.441		5.63	5±1	6	1.2440	3
2.48		5.85	5±1	6	1.2539	3
2.402	π/4-DQPSK	3.84	4±1	5	0.9802	3
2.441		3.79	4±1	5	0.9881	3
2.48		4.19	4±1	5	0.9960	3
2.402	8DPSK	3.41	4±1	5	0.9802	3
2.441		4.02	4±1	5	0.9881	3
2.48		4.33	4±1	5	0.9960	3

## Bluetooth DTS:

Transmit Frequency (GHz)	Mode	Measured Power (dBm)	Tune-up power (dBm)	Max tune-up	Result calculation	1g SAR
2.402		6.43	7±1	8	1.9558	3
2.440	GFSK	7.49	7±1	8	1.9712	3
2.48		7.60	7±1	8	1.9873	3

Conclusion:

For the max result: 0.3965≤ 3.0 for 1g SAR, No SAR is required.

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